

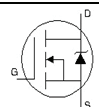
**Static @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	75	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.096	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 5mA$ ②
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	7.34	9.0	m $\Omega$	$V_{GS} = 10V, I_D = 46A$ ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 100\mu A$
$g_{fs}$	Forward Trans conductance	115	—	—	S	$V_{DS} = 50V, I_D = 46A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	20	$\mu A$	$V_{DS} = 75V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 60V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20V$

**Dynamic Electrical Characteristics @  $T_J = 25^\circ\text{C}$  (unless otherwise specified)**

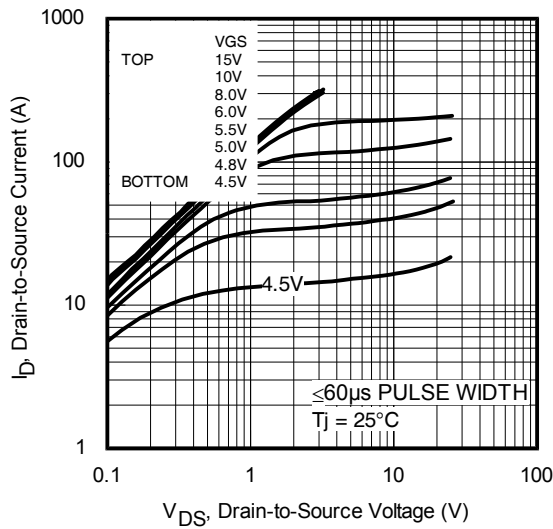
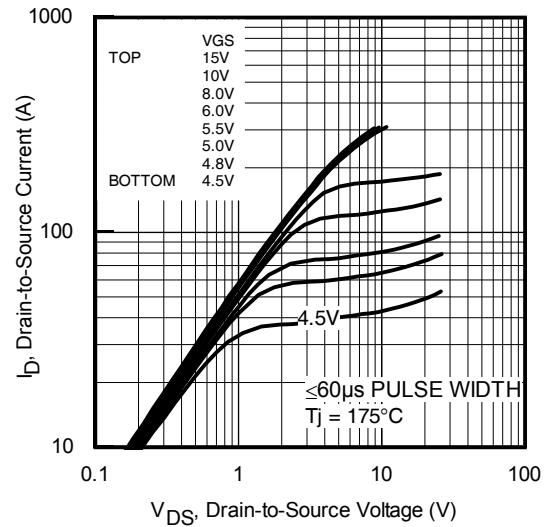
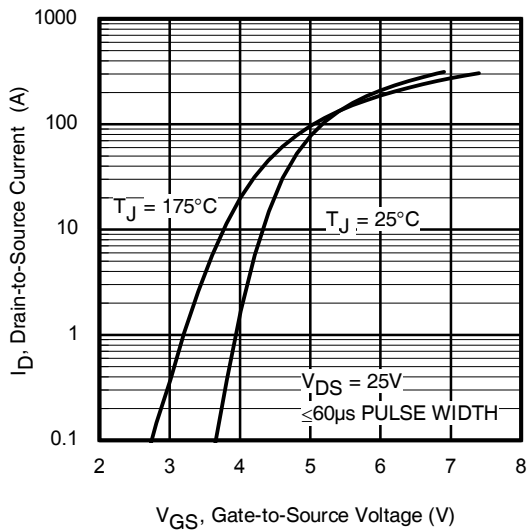
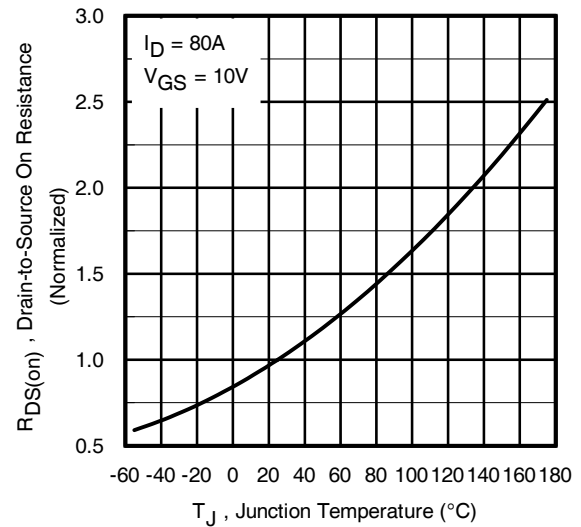
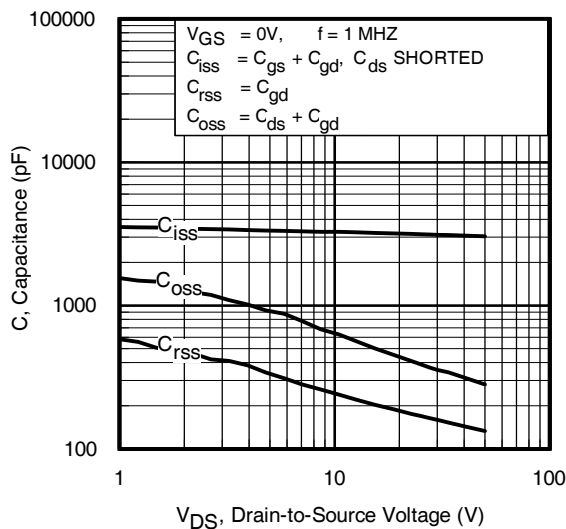
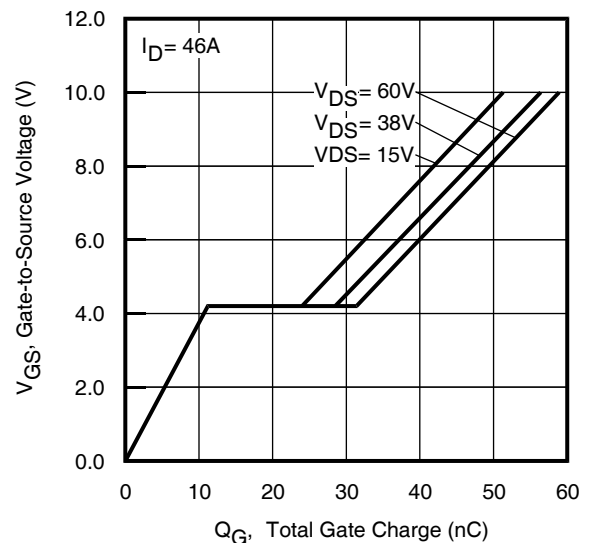
$Q_g$	Total Gate Charge	—	56	84	nC	$I_D = 46A$ $V_{DS} = 38V$ $V_{GS} = 10V$ ④
$Q_{gs}$	Gate-to-Source Charge	—	13	—		
$Q_{gd}$	Gate-to-Drain Charge	—	16	—		
$Q_{sync}$	Total Gate Charge Sync. ( $Q_g - Q_{gd}$ )	—	40	—		
$R_G$	Internal Gate Resistance	—	0.55	—	$\Omega$	
$t_{d(on)}$	Turn-On Delay Time	—	16	—	ns	$V_{DD} = 49V$ $I_D = 46A$ $R_G = 6.8\Omega$ $V_{GS} = 10V$ ④
$t_r$	Rise Time	—	110	—		
$t_{d(off)}$	Turn-Off Delay Time	—	43	—		
$t_f$	Fall Time	—	96	—		
$C_{iss}$	Input Capacitance	—	3070	—	pF	$V_{GS} = 0V$ $V_{DS} = 50V$ $f = 1.0MHz$ , See Fig. 5
$C_{oss}$	Output Capacitance	—	280	—		
$C_{rss}$	Reverse Transfer Capacitance	—	130	—		
$C_{oss\text{ eff.}(ER)}$	Effective Output Capacitance (Energy Related)	—	380	—		$V_{GS} = 0V, V_{DS} = 0V$ to $60V$ ⑥
$C_{oss\text{ eff.}(TR)}$	Effective Output Capacitance (Time Related)	—	610	—		$V_{GS} = 0V, V_{DS} = 0V$ to $60V$ ⑤

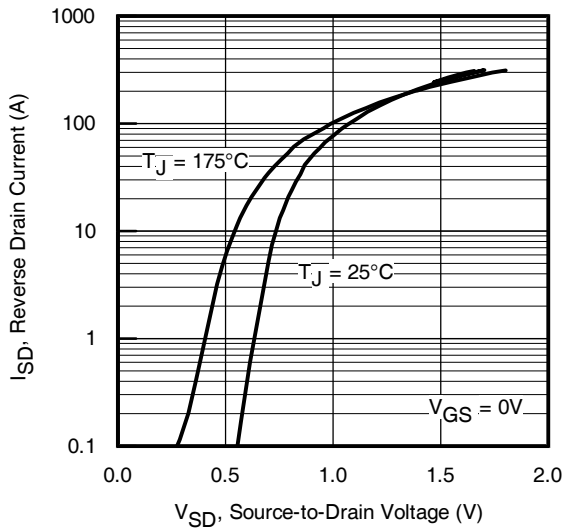
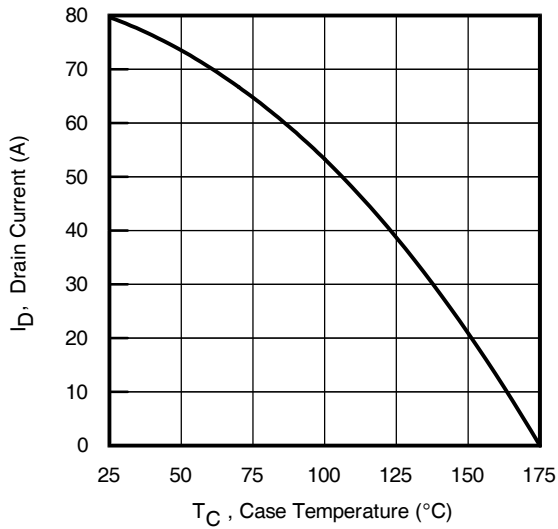
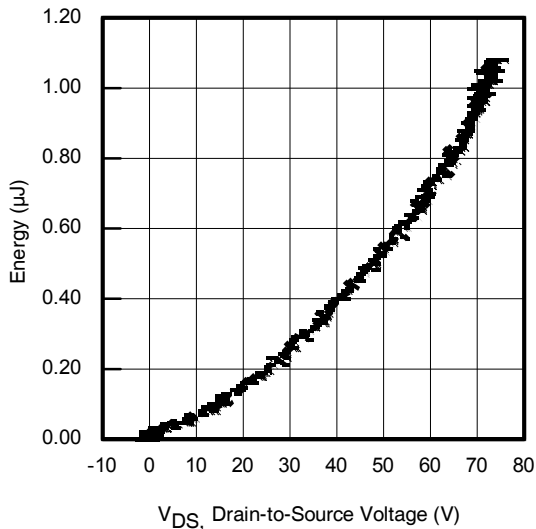
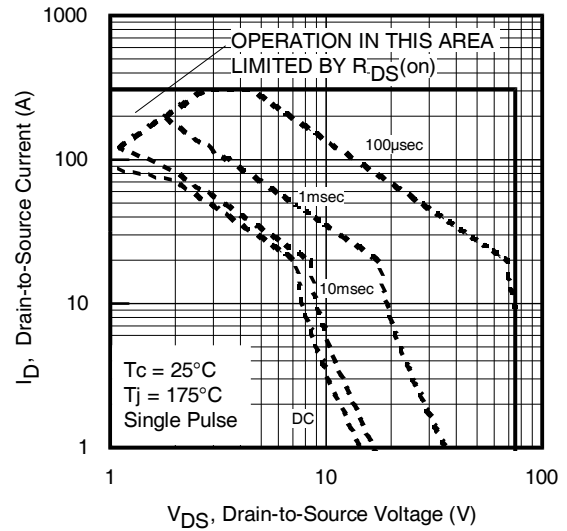
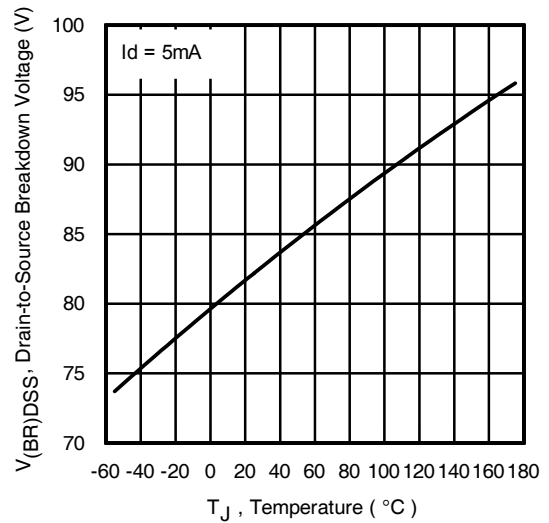
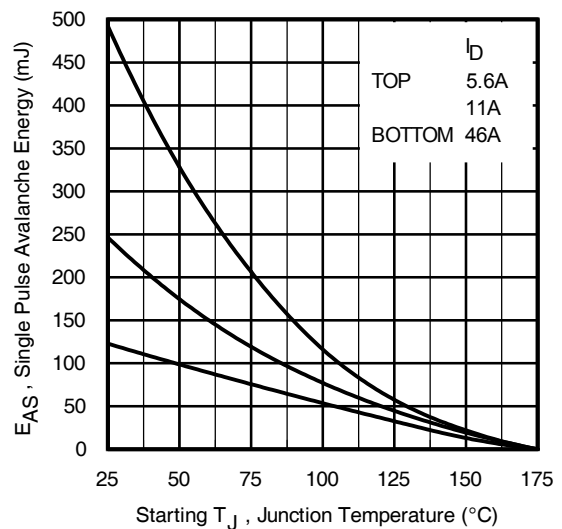
**Diode Characteristics**

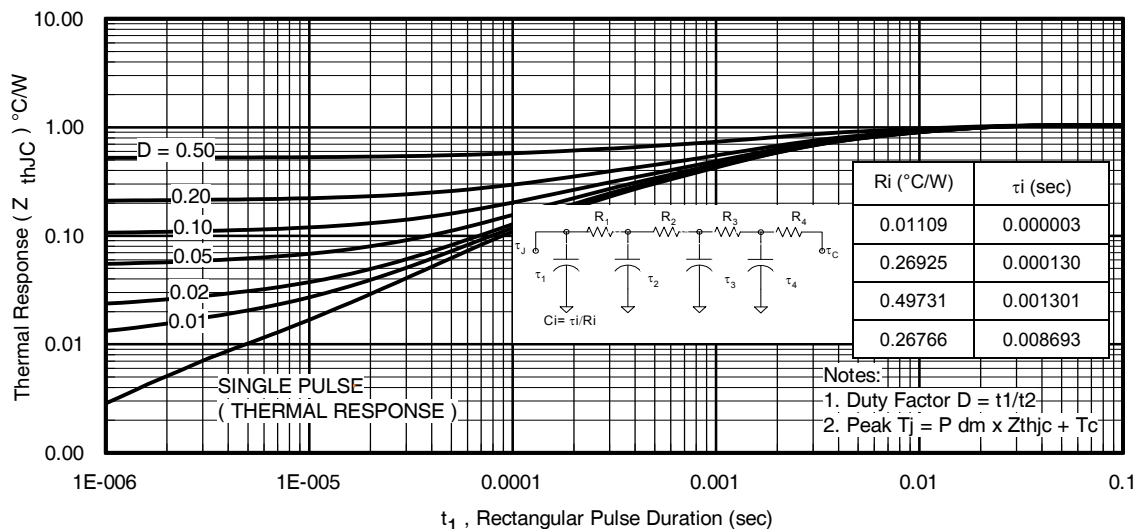
	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	80	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	310		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 46A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	33	50	ns	T <sub>J</sub> = 25°C      V <sub>DD</sub> = 64V T <sub>J</sub> = 125°C      I <sub>F</sub> = 46A, di/dt = 100A/μs ④
		—	39	59		
Q <sub>rr</sub>	Reverse Recovery Charge	—	32	48	nC	
		—	47	71		
I <sub>RRM</sub>	Reverse Recovery Current	—	1.9	—	A	T <sub>J</sub> = 25°C
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

**Notes:**

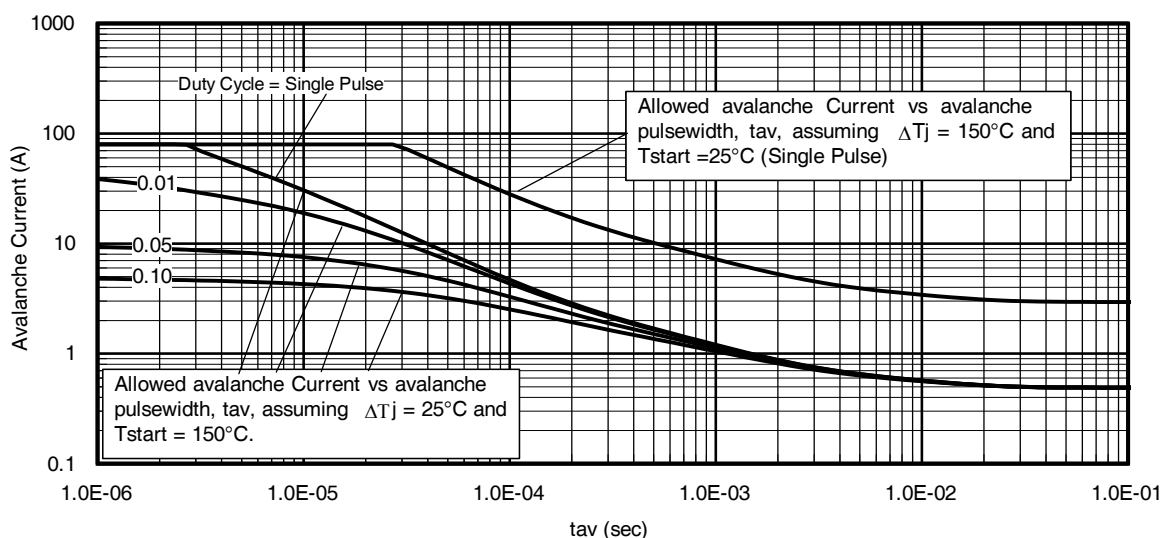
- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.12mH$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 46A$ ,  $V_{GS} = 10V$ . Part not recommended for use above this value.
- ③  $I_{SD} \leq 46A$ ,  $di/dt \leq 1920A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 175^\circ\text{C}$ .
- ④ Pulse width  $\leq 400\mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤  $C_{oss\text{ eff.}(TR)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑥  $C_{oss\text{ eff.}(ER)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- ⑦ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ⑧  $R_\theta$  is measured at  $T_J$  approximately  $90^\circ\text{C}$ .


**Fig. 1** Typical Output Characteristics

**Fig. 2** Typical Output Characteristics

**Fig. 3** Typical Transfer Characteristics

**Fig. 4** Normalized On-Resistance vs. Temperature

**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

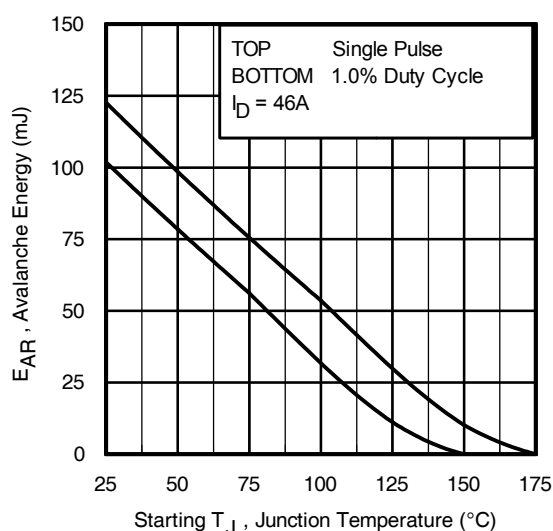

**Fig. 7** Typical Source-to-Drain Diode Forward Voltage

**Fig 9.** Maximum Drain Current vs. Case Temperature

**Fig 11.** Typical Coss Stored Energy

**Fig 8.** Maximum Safe Operating Area

**Fig 10.** Drain-to-Source Breakdown Voltage

**Fig 12.** Maximum Avalanche Energy vs. Drain Current



**Fig 13.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Fig 14.** Avalanche Current vs. Pulse width



**Notes on Repetitive Avalanche Curves , Figures 14, 15:**  
(For further info, see AN-1005 at [www.infineon.com](http://www.infineon.com))

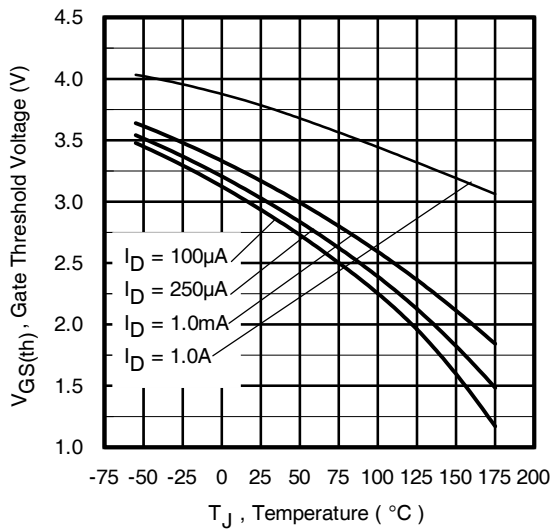
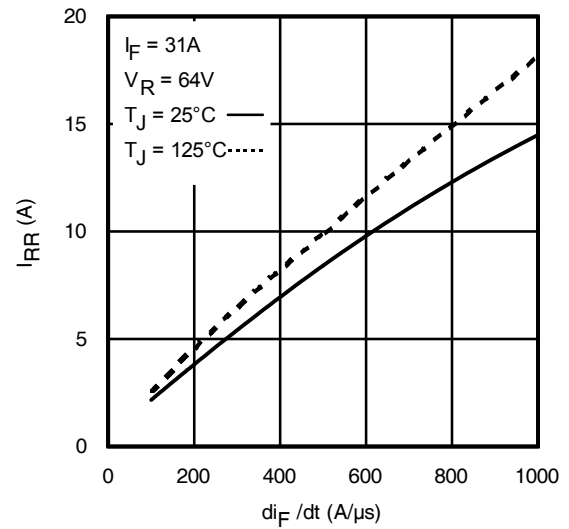
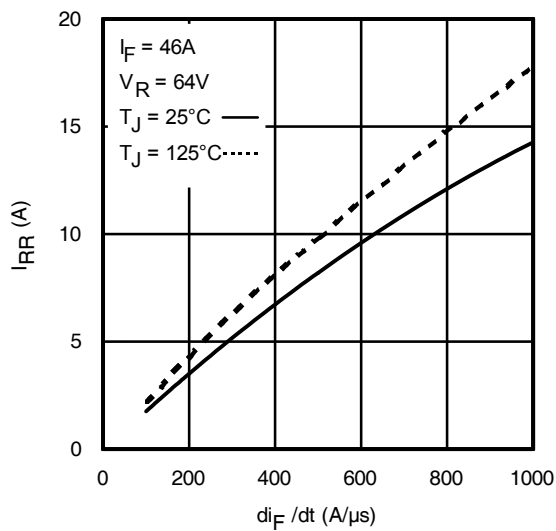
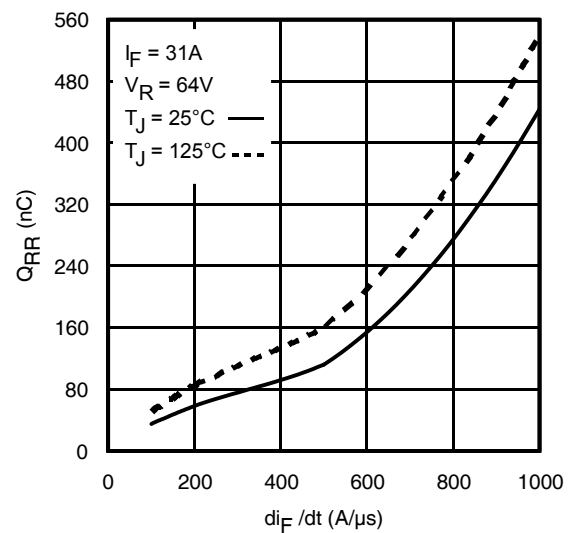
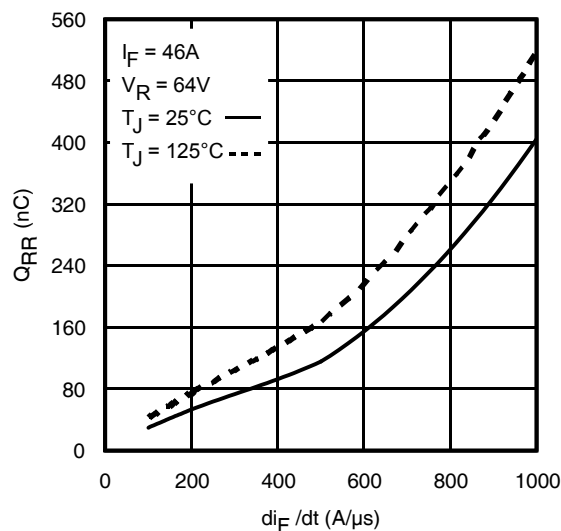
- Avalanche failures assumption:  
Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{jmax}$ . This is validated for every part type.
- Safe operation in Avalanche is allowed as long as  $T_{jmax}$  is not exceeded.
- Equation below based on circuit and waveforms shown in Figures 18a, 18b.
- $P_{D(ave)}$  = Average power dissipation per single avalanche pulse.
- $BV$  = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- $I_{av}$  = Allowable avalanche current.
- $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 13, 14).  
 $t_{av}$  = Average time in avalanche.  
 $D$  = Duty cycle in avalanche =  $t_{av} \cdot f$   
 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

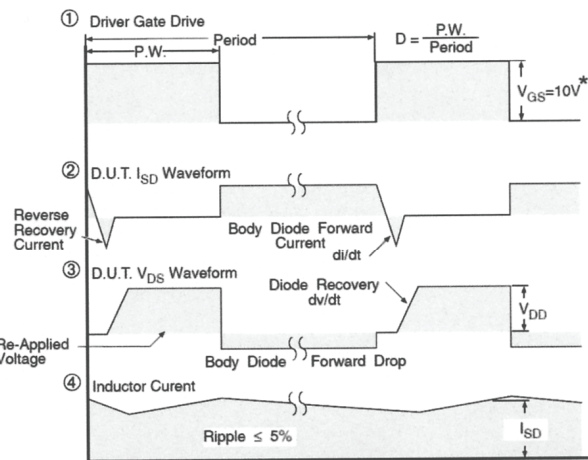
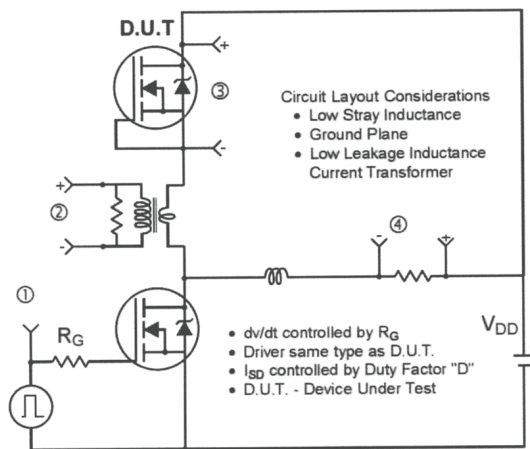
$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

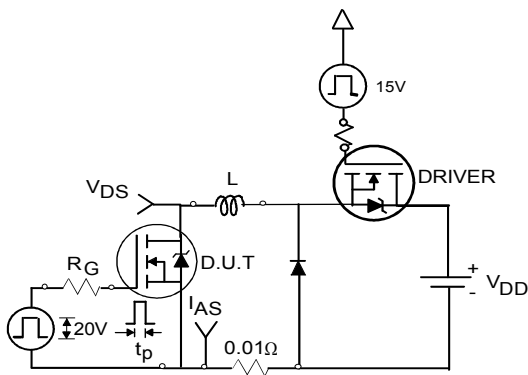
$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

**Fig 15.** Maximum Avalanche Energy vs. Temperature

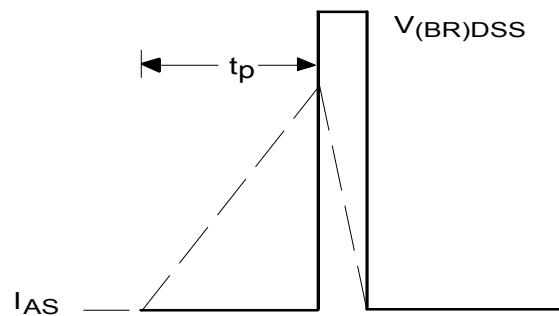

**Fig. 16.** Threshold Voltage vs. Temperature

**Fig. 17 -** Typical Recovery Current vs.  $di_F/dt$ 

**Fig. 18 -** Typical Recovery Current vs.  $di_F/dt$ 

**Fig. 19 -** Typical Stored Charge vs.  $di_F/dt$ 

**Fig. 20 -** Typical Stored Charge vs.  $di_F/dt$



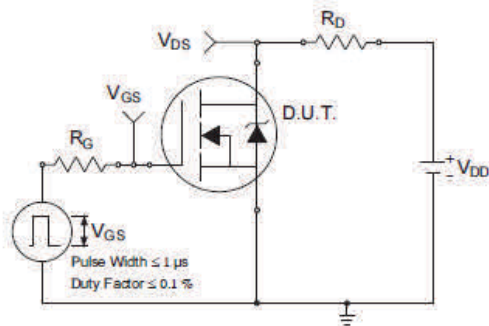
**Fig 21.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



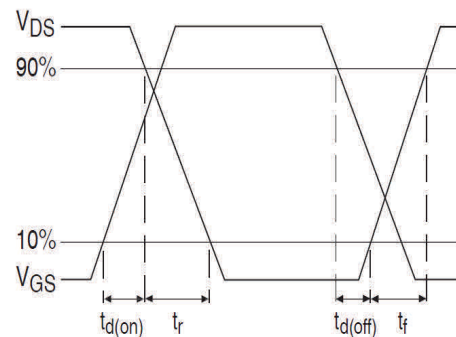
**Fig 22a.** Unclamped Inductive Test Circuit



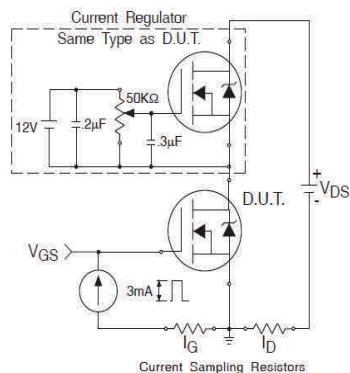
**Fig 22b.** Unclamped Inductive Waveforms



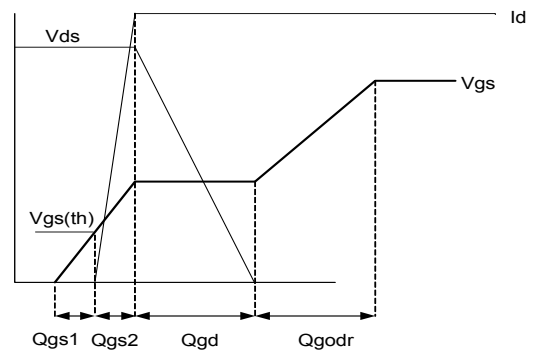
**Fig 23a.** Switching Time Test Circuit



**Fig 23b.** Switching Time Waveforms



**Fig 24a.** Gate Charge Test Circuit

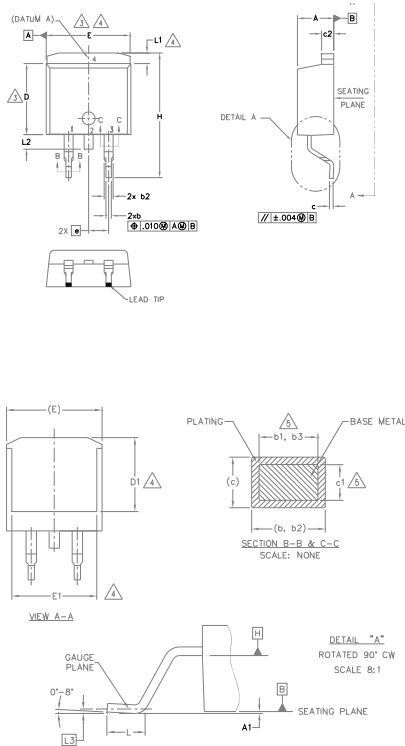


**Fig 24b.** Gate Charge Waveform

### D<sup>2</sup>Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))

NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1, b3 AND c1 APPLY TO BASE METAL ONLY.
6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
7. CONTROLLING DIMENSION: INCH.
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.



SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	
b2	1.14	1.78	.045	.070	5
b3	1.14	1.73	.045	.068	
c	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	
c2	1.14	1.65	.045	.065	5
D	8.38	9.65	.330	.380	
D1	6.86	—	.270	—	
E	9.65	10.67	.380	.420	
E1	6.22	—	.245	—	3,4
e	2.54 BSC		.100 BSC		4
H	14.61	15.88	.575	.625	4
L	1.78	2.79	.070	.110	
L1	—	1.68	—	.066	
L2	—	1.78	—	.070	
L3	0.25 BSC		.010 BSC		

### LEAD ASSIGNMENTS

## DIODES

- 1.- ANODE (TWO DIE) / OPEN (ONE DIE)
- 2, 4.- CATHODE
- 3.- ANODE

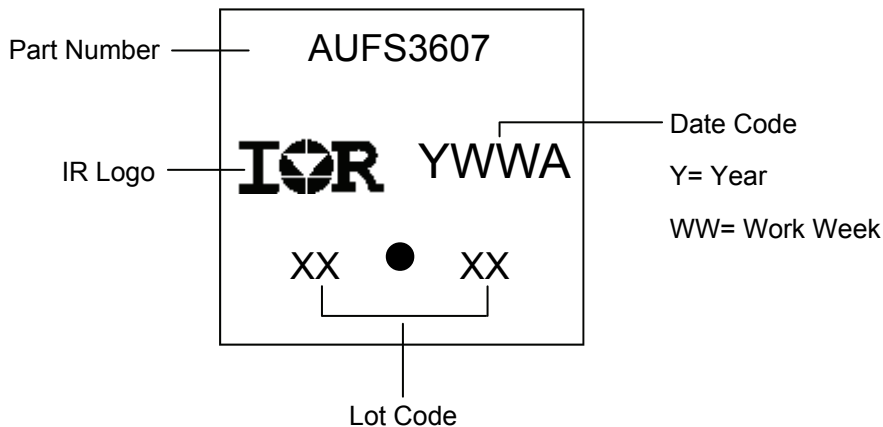
## HEXFET

- |              |                  |
|--------------|------------------|
| 1.- GATE     | 1.- GATE         |
| 2, 4.- DRAIN | 2, 4.- COLLECTOR |
| 3.- SOURCE   | 3.- EMITTER      |

## IGBTs, CoPACK

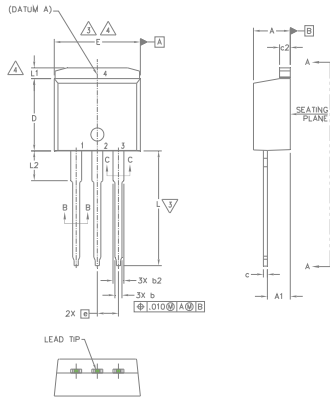
- 1.- GATE  
2, 4.- COLLECTOR  
3.- EMITTER

## D<sup>2</sup>Pak (TO-263AB) Part Marking Information



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

## TO-262 Package Outline (Dimensions are shown in millimeters (inches))



NOTES:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

### LEAD ASSIGNMENTS

IGBTs, CoPACK

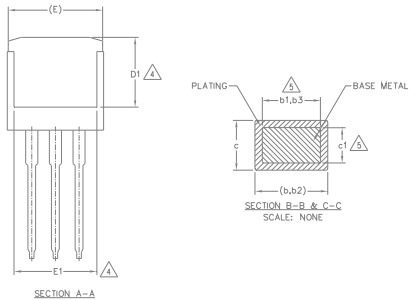
- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

## HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE
- 4.- DRAIN

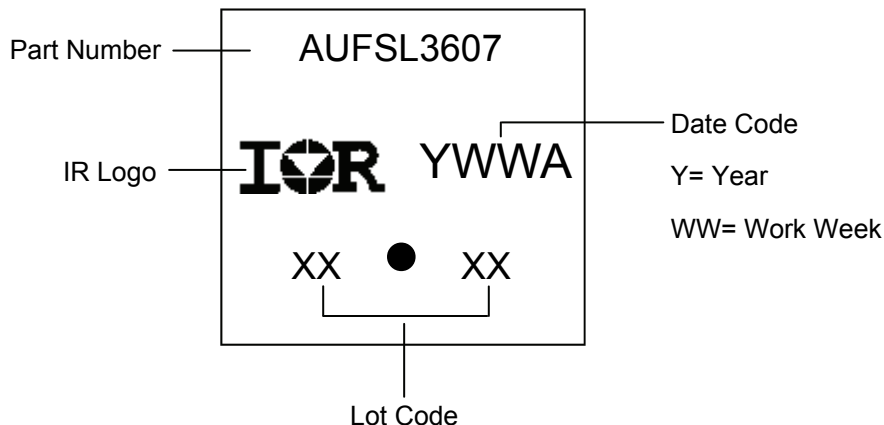
## DIODES

- 1.- ANODE (TWO DIE) / OPEN (ONE DIE)
- 2, 4.- CATHODE
- 3.- ANODE



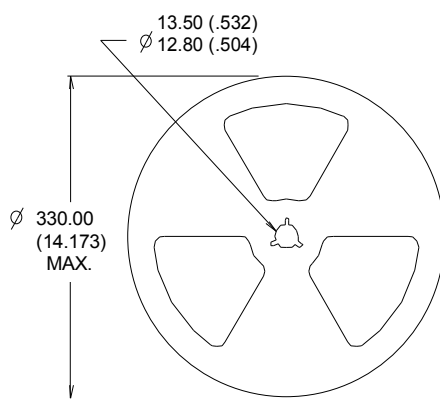
S Y M B O L	DIMENSIONS				N O T E S
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	4.06	4.83	.160	.190	5
A1	2.03	3.02	.080	.119	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	
b2	1.14	1.78	.045	.070	5
b3	1.14	1.73	.045	.068	
c	0.38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	
c2	1.14	1.65	.045	.065	3
D	8.38	9.65	.330	.380	
D1	6.86	—	.270	—	
E	9.65	10.67	.380	.420	
E1	6.22	—	.245		4
e	2.54 BSC		.100 BSC		4
L	13.46	14.10	.530	.555	
L1	—	1.65	—	.065	
L2	3.56	3.71	.140	.146	

## TO-262 Part Marking Information

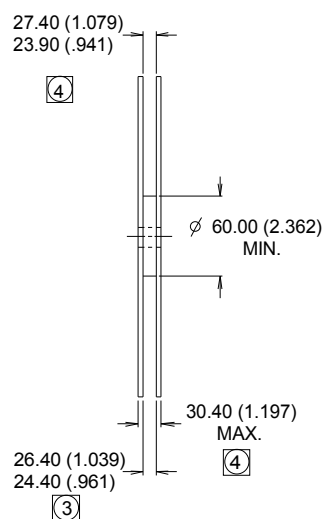


Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>



[illegible]

- NOTES :
1. COMFORMS TO EIA-418.
  2. CONTROLLING DIMENSION: MILLIMETER.
  - ③ DIMENSION MEASURED @ HUB.
  - ④ INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Downloaded from [Arrow.com](http://Arrow.com).

**Qualification Information**

Qualification Level		Automotive (per AEC-Q101)	
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.	
Moisture Sensitivity Level		D <sup>2</sup> -Pak	MSL1
		TO-262	
ESD	Machine Model	Class M4 (+/- 600V) <sup>†</sup> AEC-Q101-002	
	Human Body Model	Class H1C (+/- 2000V) <sup>†</sup> AEC-Q101-001	
	Charged Device Model	Class C5 (+/- 2000V) <sup>†</sup> AEC-Q101-005	
RoHS Compliant		Yes	

† Highest passing voltage.

**Revision History**

Date	Comments
10/27/2015	<ul style="list-style-type: none"> <li>Updated datasheet with corporate template</li> <li>Corrected ordering table on page 1.</li> </ul>
02/12/2016	<ul style="list-style-type: none"> <li>Corrected Fig.6 label from V<sub>DS</sub>=24V &amp; 15V to V<sub>DS</sub>= 60V,38V,15V-on page 3.</li> </ul>

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